

ISSUE CLASSIFICATION	
Class	Subclass

U.S. ~~UTILITY~~ Patent Application

O.I.P.E.

PATENT DATE

SCANNED

Q.A

APPLICATION NO. 09/943696	CONT/PRIOR	CLASS 356	SUBCLASS 219	ART UNIT 2877	EXAMINER T. J. [illegible]
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APPLICANTS

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Method of measuring surface plasmon resonance using interference structure of reflected beam profile

[illegible]**ISSUING CLASSIFICATION**

ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
INTERNATIONAL CLASSIFICATION							

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	_____ (Assistant Examiner) (Date)		NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____	_____ (Primary Examiner) (Date)		ISSUE FEE	
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